



# CERTIFICATE OF ACCREDITATION

## The ANSI National Accreditation Board

Hereby attests that

**MicroscOptics, Inc.**  
**9126 Pineview Lake Court**  
**Linden, MI 48451**

Fulfills the requirements of

**ISO/IEC 17025:2017**

and national standard

**ANSI/NCSL Z540-1-1994 (R2002)**

In the field of

**CALIBRATION**

This certificate is valid only when accompanied by a current scope of accreditation document.  
The current scope of accreditation can be verified at [www.anab.org](http://www.anab.org).

A handwritten signature in black ink, appearing to be 'J. Stine', is positioned above a horizontal line.

Jason Stine, Vice President

Expiry Date: 10 April 2028

Certificate Number: AC-1218



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.  
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory  
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



**SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017**

**AND**

**ANSI/NCSL Z540-1-1994 (R2002)**

**MicroscOptics, Inc.**

9126 Pineview Lake Court  
Linden, MI 48451

James L. Short 248-328-0433

**CALIBRATION**

ISO/IEC 17025 Accreditation Granted: **09 April 2026**

Certificate Number: **AC-1218** Certificate Expiry Date: **10 April 2028**

**Length – Dimensional Metrology**

<b>Parameter/Equipment</b>	<b>Range</b>	<b>Expanded Uncertainty of Measurement (+/-)</b>	<b>Reference Standard, Method, and/or Equipment</b>
Microscopes <sup>1</sup> (Eyepiece Micrometers and Image Systems) Length & Linearity	(0.000 4 to 1) in (0.01 to 25) mm	14 μin 0.34 μm	Comparison to Stage Micrometer
Linear Stage Measurement Devices <sup>1</sup> (Optical & Digital Comparators, MeasureScopes, and CNC Video Microscopes) Length & Linearity X and Y axes Z-axis	(1 to 12) in (0.01 to 300) mm (0.02 to 105) mm	175 μin 1.1 μm 0.32 μm	Comparisons to Glass Scales, Step Gage, Gage Blocks
Optical and Contact Profilometers <sup>1</sup> Ra Step Height	Up to 3 μm (0.02 to 105) mm	40 nm 0.13 μm	Comparisons to Surface Finish Specimen Step Gage, Gage Blocks

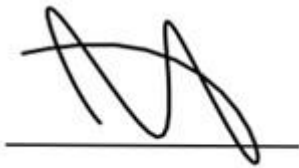
**Length – Dimensional Metrology**

Parameter/Equipment	Range	Expanded Uncertainty of Measurement (+/-)	Reference Standard, Method, and/or Equipment
Angle Measuring Devices <sup>1,2</sup> (Optical & Digital Comparators and Image Systems)	(0 to 360)°	2'	Comparison to Angle Blocks
Magnification <sup>1</sup> (Optical & Digital Comparators, Eye Loupes, and Image Systems)	(1 to 2 000) X	0.13 % of the nominal magnification	Comparison to Glass Scale

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 ( $k=2$ ), corresponding to a confidence level of approximately 95%.

Notes:

1. On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope.
2. ' = arc-minute.
3. Unless otherwise specified in the far-right hand column, the calibration procedure being utilized by the laboratory was written internally.



Jason Stine, Vice President